

N-Channel Power MOSFET (4A, 600Volts)

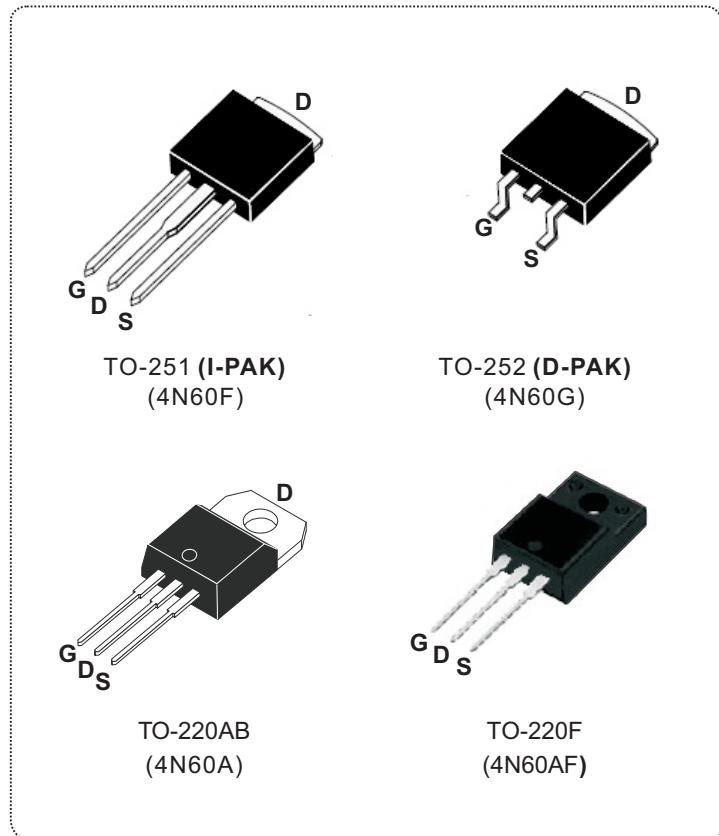
DESCRIPTION

The Nell **4N60** is a three-terminal silicon device with current conduction capability of 4A, fast switching speed, low on-state resistance, breakdown voltage rating of 600V, and max. threshold voltage of 4 volts.

They are designed for use in applications such as switched mode power supplies, DC to DC converters, PWM motor controls, bridge circuits and general purpose switching applications.

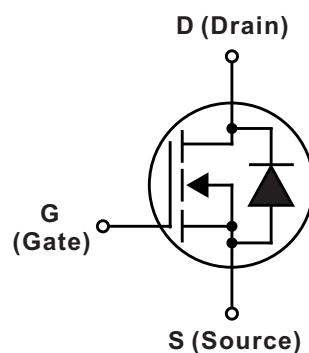
FEATURES

- $R_{DS(ON)} = 2.5\Omega @ V_{GS} = 10V$
- Ultra low gate charge(20nC max.)
- Low reverse transfer capacitance ($C_{RSS} = 8pF$ typical)
- Fast switching capability
- 100% avalanche energy specified
- Improved dv/dt capability
- 150°C operation temperature



PRODUCT SUMMARY

I_D (A)	4
V_{DSS} (V)	600
$R_{DS(ON)}$ (Ω)	2.5 @ $V_{GS} = 10V$
Q_G (nC) max.	20



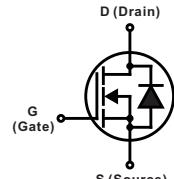
ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ unless otherwise specified)				
SYMBOL	PARAMETER	TEST CONDITIONS	VALUE	UNIT
V_{DSS}	Drain to Source voltage	$T_J=25^\circ\text{C}$ to 150°C	600	V
V_{DGR}	Drain to Gate voltage	$R_{GS}=20\text{ k}\Omega$	600	
V_{GS}	Gate to Source voltage		± 30	
I_D	Continous Drain Current	$T_C=25^\circ\text{C}$	4	A
		$T_C=100^\circ\text{C}$	2.48	
I_{DM}	Pulsed Drain current(Note 1)		16	
I_{AR}	Avalanche current(Note 1)		4	
E_{AR}	Repetitive avalanche energy(Note 1)	$I_{AR}=4\text{ A}$, $R_{GS}=50\Omega$, $V_{GS}=10\text{ V}$	10.6	mJ
E_{AS}	Single pulse avalanche energy (Note 2)	$I_{AS}=4\text{ A}$, $L = 30\text{ mH}$	260	
dv/dt	Peak diode recovery dv/dt (Note 3)		4.5	V/ns
P_D	Total power dissipation (Derate above 25°C)	$T_C=25^\circ\text{C}$	TO-251/ TO-252	50 (0.39)
			TO-220AB	100 (0.8)
			TO-220F	36 (0.26)
T_J	Operation junction temperature		-55 to 150	°C
T_{STG}	Storage temperature		-55 to 150	
T_L	Maximum soldering temperature, for 10 seconds	1.6mm from case	300	
	Mounting torque, #6-32 or M3 screw		10 (1.1)	lbf·in (N·m)

Note: 1.Repetitive rating: pulse width limited by junction temperature.

2. $I_{AS} = 4\text{ A}$, $V_{DD} = 50\text{ V}$, $L = 30\text{ mH}$, $R_{GS} = 25\Omega$, starting $T_J=25^\circ\text{C}$.

3. $I_{SD} \leq 4\text{ A}$, $di/dt \leq 200\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, starting $T_J=25^\circ\text{C}$.

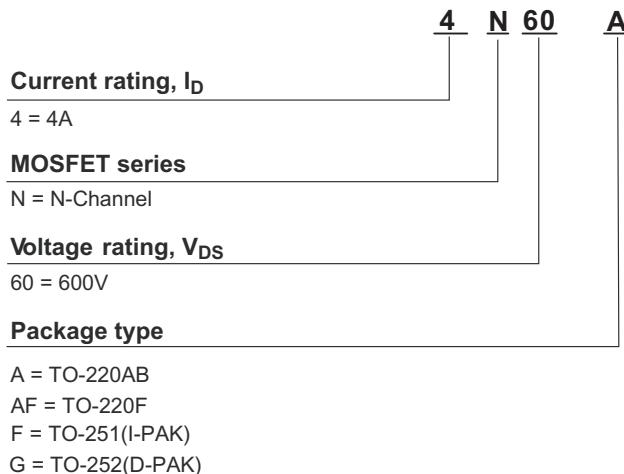
THERMAL RESISTANCE						
SYMBOL	PARAMETER		Min.	Typ.	Max.	UNIT
$R_{th(j-c)}$	Thermal resistance, junction to case	TO-251/ TO-252			2.5	°C/W
		TO-220AB			1.2	
		TO-220F			3.5	
$R_{th(j-a)}$	Thermal resistance, junction to ambient	TO-251/TO-252			85	°C/W
		TO-220AB			62.5	
		TO-220F			62.5	

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)							
SYMBOL	PARAMETER	TEST CONDITIONS		Min.	Typ.	Max.	UNIT
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$V_{(\text{BR})\text{DSS}}$	Drain to source breakdown voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$		600			V
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown voltage temperature coefficient	$I_D = 250\mu\text{A}$, $V_{DS} = V_{GS}$		0.6			$\text{V}/^\circ\text{C}$
I_{DSS}	Drain to source leakage current	$V_{DS}=600\text{V}$, $V_{GS}=0\text{V}$	$T_C = 25^\circ\text{C}$		10		μA
		$V_{DS}=480\text{V}$, $V_{GS}=0\text{V}$	$T_C = 125^\circ\text{C}$		100		
I_{GSS}	Gate to source forward leakage current	$V_{GS} = 30\text{V}$, $V_{DS} = 0\text{V}$			100		nA
	Gate to source reverse leakage current	$V_{GS} = -30\text{V}$, $V_{DS} = 0\text{V}$				-100	
© ON CHARACTERISTICS							
$R_{DS(\text{ON})}$	Static drain to source on-state resistance	$I_D = 2\text{A}$, $V_{GS} = 10\text{V}$			2.2	2.5	Ω
$V_{GS(\text{TH})}$	Gate threshold voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$		2.0		4.0	V
g_{FS}	Forward transconductance	$V_{DS}=40\text{V}$, $I_D=2\text{A}$			4.7		S
© DYNAMIC CHARACTERISTICS							
C_{ISS}	Input capacitance	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$			520	670	pF
C_{OSS}	Output capacitance				70	90	
C_{RSS}	Reverse transfer capacitance				8.0	11	
© SWITCHING CHARACTERISTICS							
$t_{d(\text{ON})}$	Turn-on delay time	$V_{DD} = 300\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 4\text{A}$, $R_{GS} = 25\Omega$ (Note 1, 2)			13	35	ns
t_r	Rise time				45	100	
$t_{d(\text{OFF})}$	Turn-off delay time				25	60	
t_f	Fall time				35	80	
Q_G	Total gate charge	$V_{DD} = 480\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 4\text{A}$ (Note 1, 2)			15	20	nC
Q_{GS}	Gate to source charge				3.5		
Q_{GD}	Gate to drain charge (Miller charge)				7.0		
SOURCE TO DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)							
SYMBOL	PARAMETER	TEST CONDITIONS		Min.	Typ.	Max.	UNIT
V_{SD}	Diode forward voltage	$I_{SD} = 4\text{A}$, $V_{GS} = 0\text{V}$				1.4	V
I_s (I_{SD})	Continuous source to drain current		Integral reverse P-N junction diode in the MOSFET			4	A
I_{SM}	Pulsed source current					16	
t_{rr}	Reverse recovery time				250		ns
Q_{rr}	Reverse recovery charge	$I_{SD} = 4\text{A}$, $V_{GS} = 0\text{V}$, $dI_F/dt = 100\text{A}/\mu\text{s}$			1.5		μC

Note: 1. Pulse test: Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

ORDERING INFORMATION SCHEME



■ TEST CIRCUITS AND WAVEFORMS

Fig.1A Peak diode recovery dv/dt test circuit

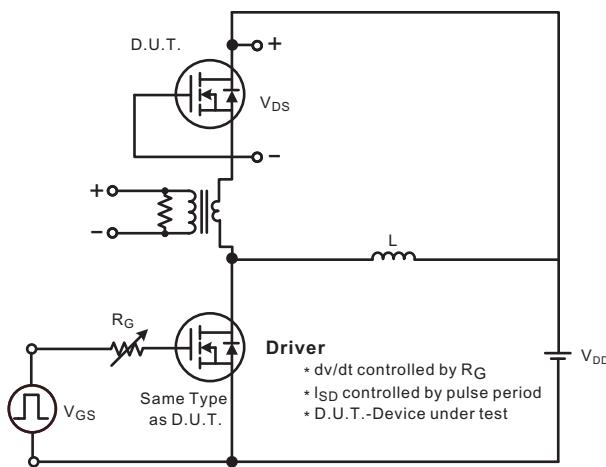
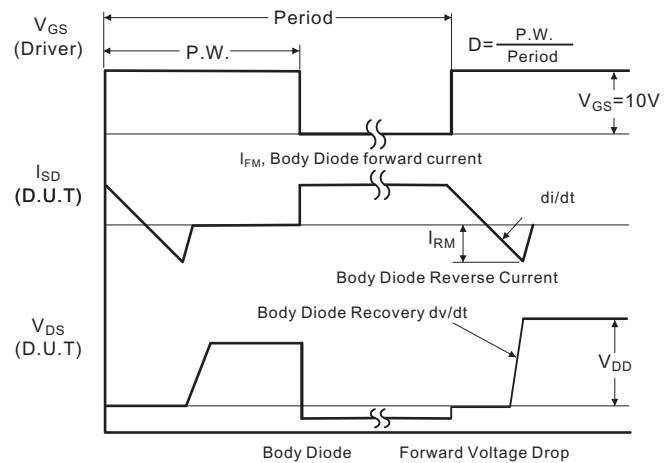
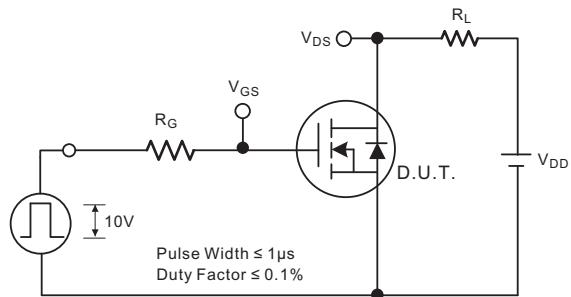
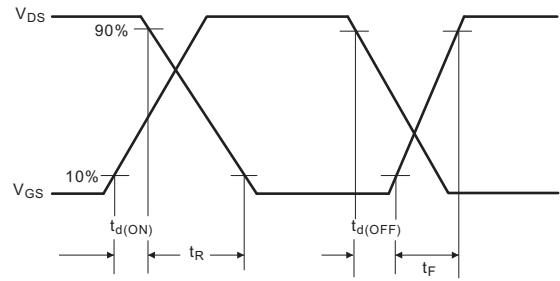
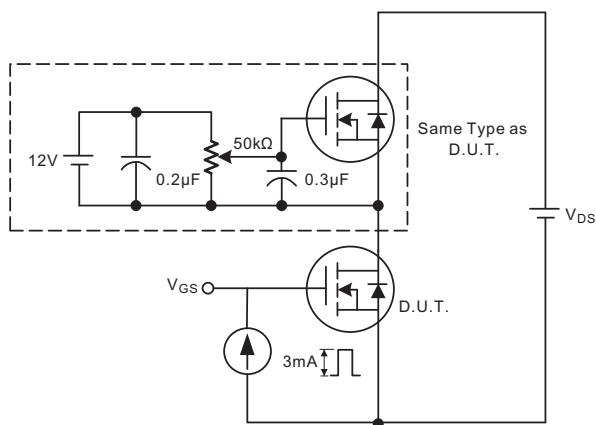
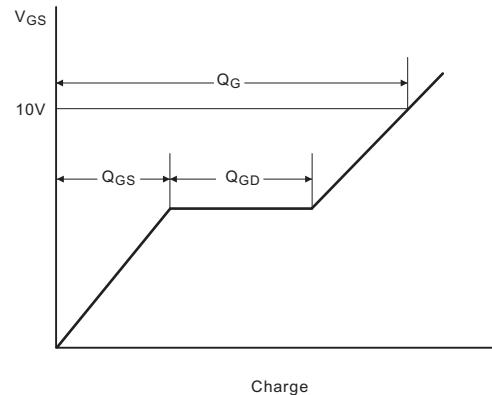
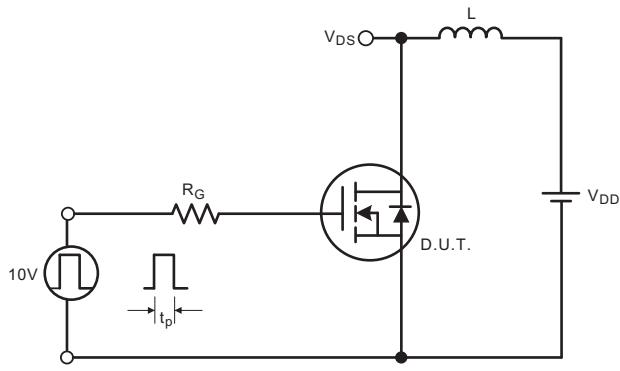
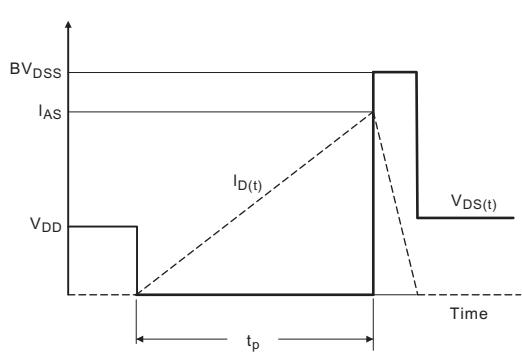


Fig.1B Peak diode recovery dv/dt waveforms



■ TEST CIRCUITS AND WAVEFORMS(Cont.)
Fig.2A Switching test circuit

Fig.2B Switching Waveforms

Fig.3A Gate charge test circuit

Fig.3B Gate charge waveform

Fig.4A Unclamped Inductive switching test circuit

Fig.4B Unclamped Inductive switching waveforms


■ TYPICAL CHARACTERISTICS

Fig.1 Breakdown voltage variation vs. Temperature

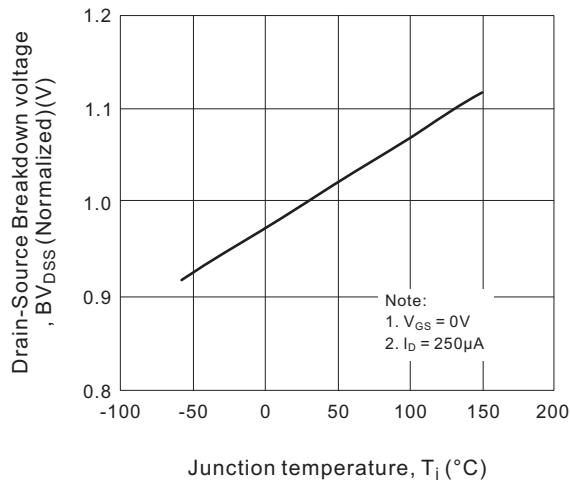


Fig.2 On-Resistance variation vs. junction vs. temperature

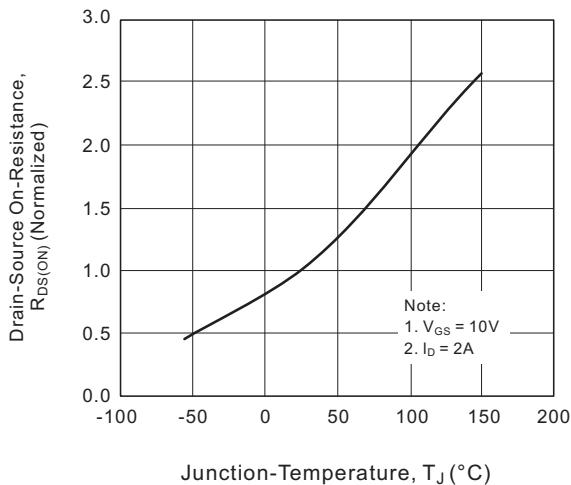


Fig.3-1 Maximum Safe operating area (for 4N60A)

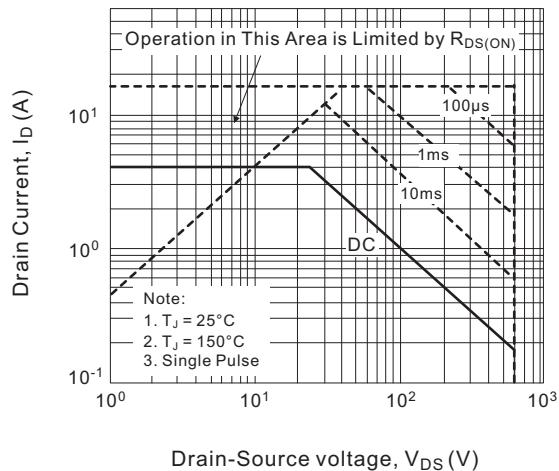


Fig.3-2 Maximum Safe operating area (for 4N60AF)

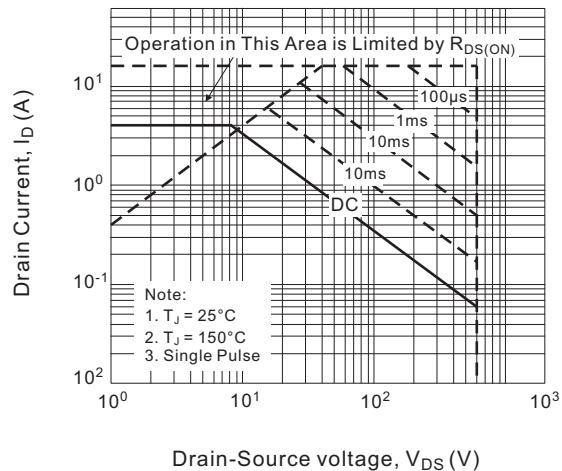


Fig.3-3 Maximum Safe operating area (for 4N60F/4N60G)

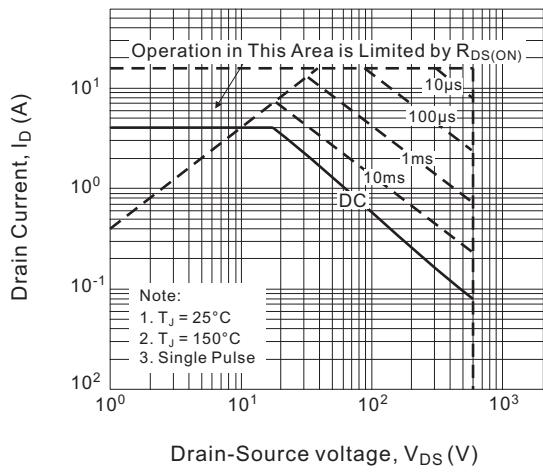
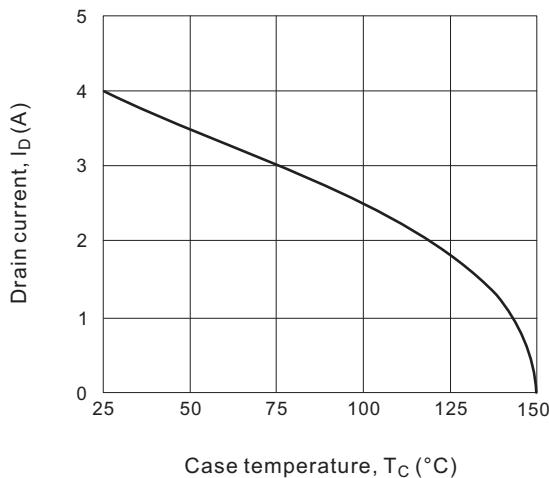


Fig.4 Maximum drain current vs. Case temperature



■ TYPICAL CHARACTERISTICS

Fig.5 On-State characteristics

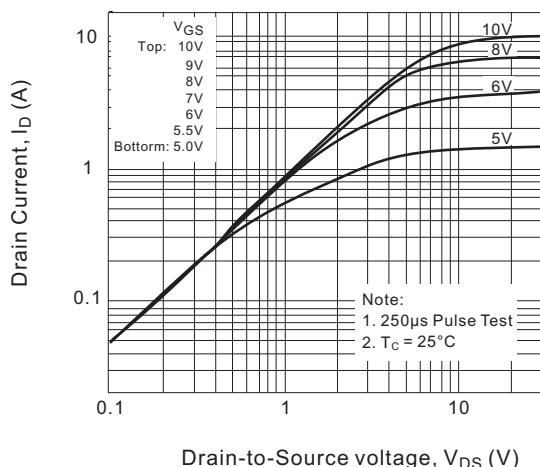


Fig.6 Transfer characteristics

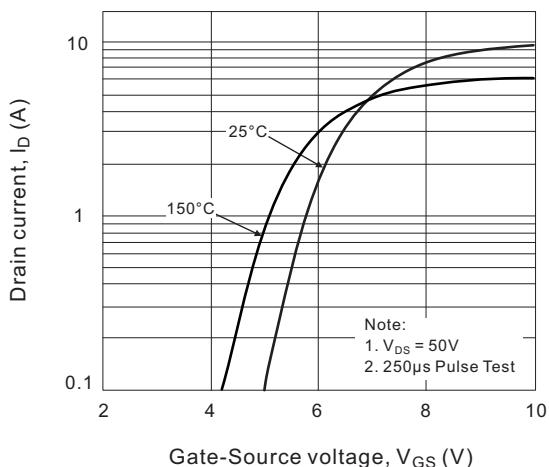


Fig.7 On-Resistance variation vs drain current and gate voltage

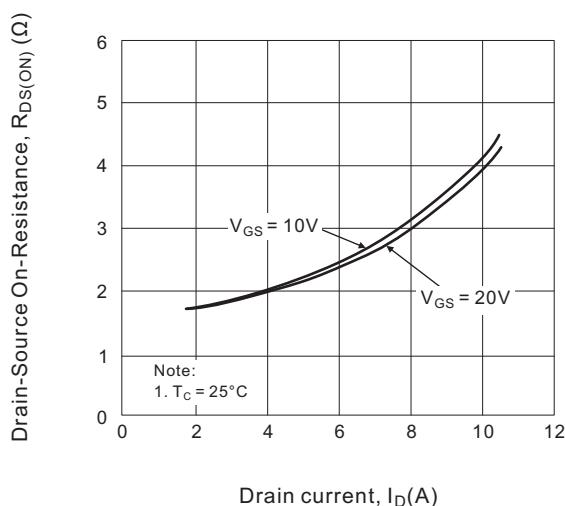


Fig.8 Body diode forward voltage variation vs. source current and temperature

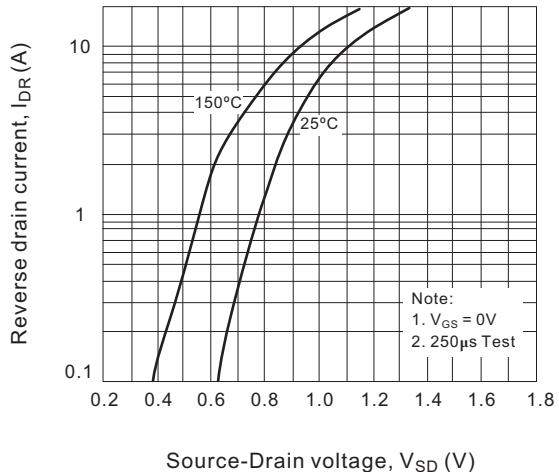


Fig.9 Capacitance characteristics (Non-Repetitive)

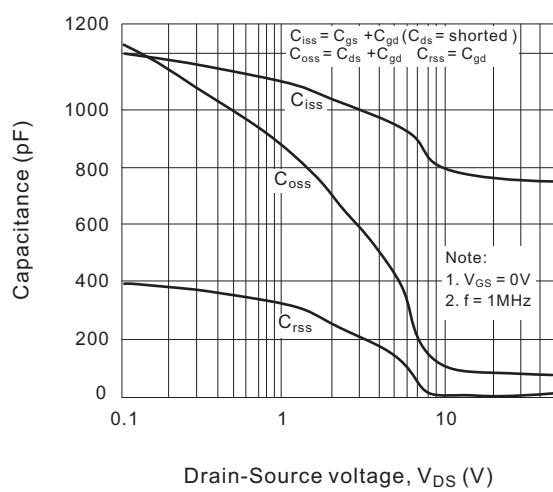
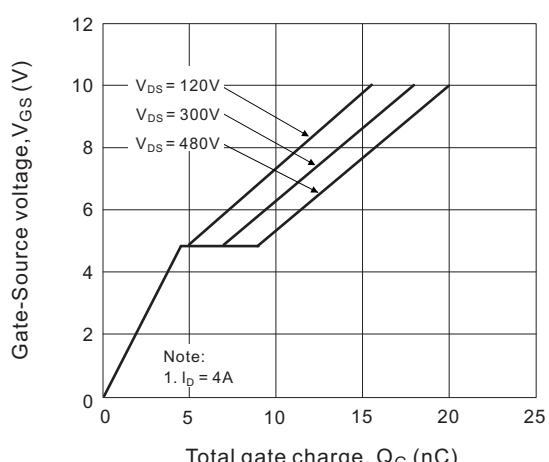


Fig.10 Gate charge characteristics



■ TYPICAL CHARACTERISTICS

Fig.11-1 Transient thermal response curve for 4N60A

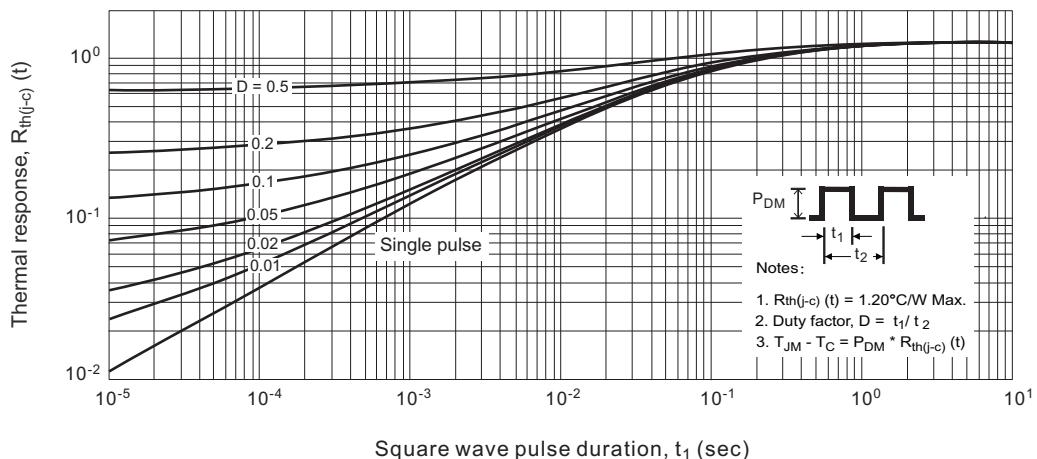


Fig.11-2 Transient thermal response curve for 4N60AF

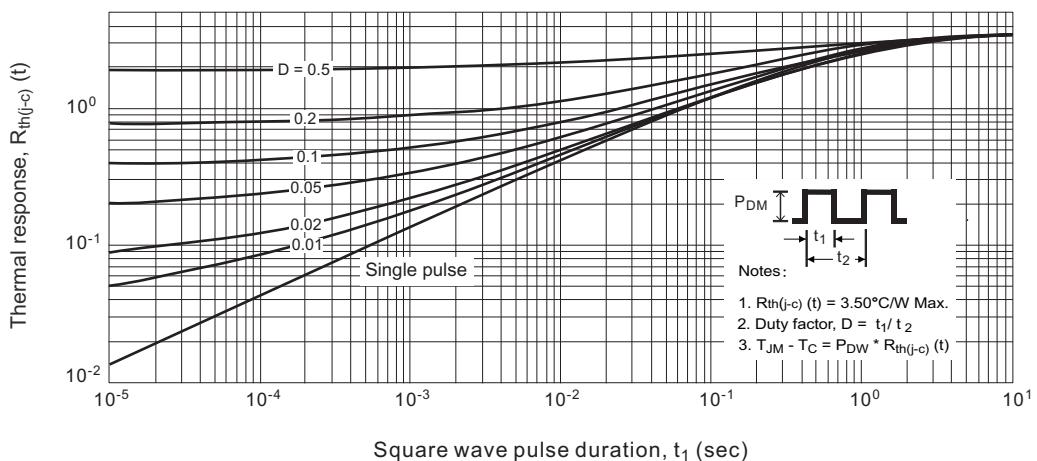
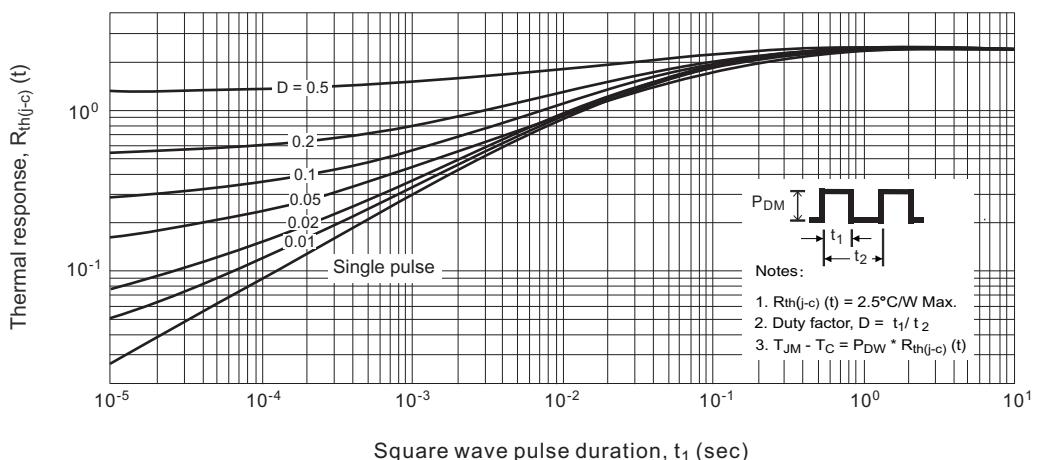
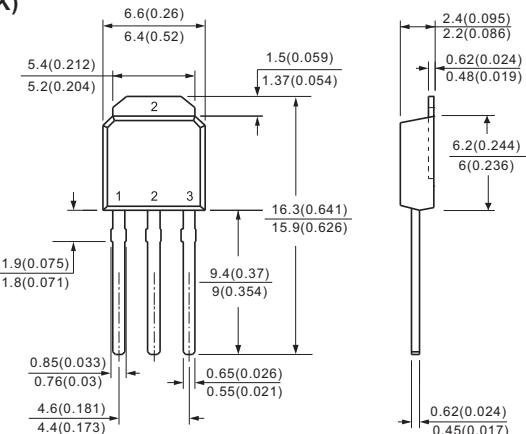
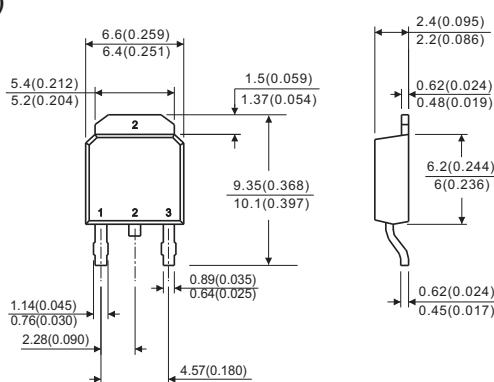
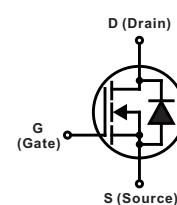
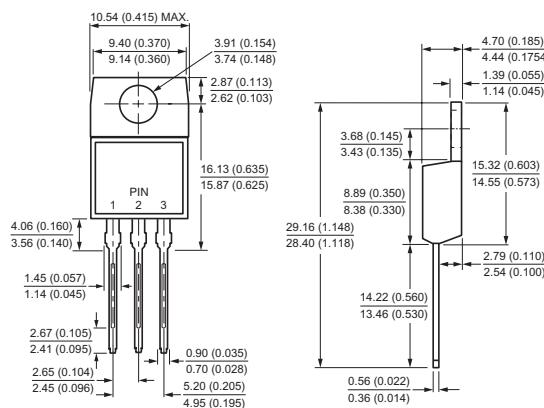


Fig.11-3 Transient thermal response curve (for 4N60F/4N60G)



■ TYPICAL CHARACTERISTICS
Case Style
**TO-251
(I-PAK)**

**TO-252
(D-PAK)**

TO-220AB


All dimensions in millimeters(inches)

Case Style

